



IEEE International Test Conference, India 2019 **July 21-23, The Leela Palace, Bengaluru**

Register for ITC India, 2019 Conference

Greetings!!

We are pleased to announce that registration is now open for ITC India 2019.

This year's event will be held at "The Leela Palace", Bengaluru between the 21st and 23rd July 2019. At ITC India, we are keen to ensure that all of our delegates and speakers have an exceptional opportunity to learn, network and share with fellow practitioners in the field of VLSI Test and Automation. We have planned sessions on wide range of topics such as emerging test needs for Artificial intelligence, Automotive and IoT, Hardware security, Test standards, Test methodologies, Memory Test, Diagnosis, emerging DFT architectures etc. that enable a rewarding experience to broad spectrum of test community.

Here is a preview of what you can expect at this year's conference:

- Keynotes from Industry leaders in the Test arena
- 6 Tutorials from Industry/Academia (Day 1)
- 2 days of Technical Program - 8 sessions (Day 2 & 3)
- Panel discussion, Demo, Booth/Exhibits and Networking

Visit our [website for more information](#).

We are looking forward to seeing you at the conference!!

Navin Bishnoi
General Chair, ITC India, 2019

Keynote Speakers



Janusz Rajski,
Vice President,
Mentor – A Siemens
Business



Michael Campbell,
Senior Vice President,
Qualcomm



Kaushik Narayanun,
Senior Director,
NVIDIA



Rohit Kapur,
Distinguished Engineer,
Cadence



Amit Sanghani,
Vice President,
Synopsys

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